

Annex C: Calibration Reports
Tested Model : X109
Report Number: WSCT-ANAB-R&E250900073A-SAR



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Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 0108

Client
WSCT
Shenzhen

Certificate No. D2550V2-1015_Aug24

CALIBRATION CERTIFICATE

Object D2550V2 - SN: 1015

Calibration procedure(s) QA CAL-05.v12
Calibration Procedure for SAR Validation Sources between 0.7 - 3 GHz

Calibration date August 16, 2024

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^\circ\text{C}$ and humidity $< 70\%$.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Cal
Power Sensor R&S NRP-33T	SN: 100967	28-Mar-24 (No. 217-04038)	Mar-25
Power Sensor R&S NRP18A	SN: 101859	21-Mar-24 (No. 4030A315007801)	Mar-25
Spectrum Analyzer R&S FSV40	SN: 101832	25-Jan-24 (No. 4030-315007551)	Jan-25
Mismatch; Short [S4188] Attenuator [S4423]	SN: 1152	28-Mar-24 (No. 217-04050)	Mar-25
OCP DAK-12	SN: 1016	05-Oct-23 (No. OCP-DAK12-1016_Oct23)	Oct-24
OCP DAK-3.5	SN: 1249	05-Oct-23 (No. OCP-DAK3.5-1249_Oct23)	Oct-24
Reference Probe EX3DV4	SN: 7349	03-Jun-24 (No. EX3-7349_Jun24)	Jun-25
DAE4ip	SN: 1836	10-Jan-24 (No. DAE4ip-1836_Jan24)	Jan-25

Secondary Standards	ID	Check Date (in house)	Scheduled Check
ACAD Source Box	SN: 1000	28-May-24 (No. 675-ACAD_Source_Box-240528)	May-25
Signal Generator R&S SMB100A	SN: 182081	28-May-24 (No. 0001-300719404)	May-25
Mismatch; SMA	SN: 1102	22-May-24 (No. 675-Mismatch_SMA-240522)	May-25

	Name	Function	Signature
Calibrated by	Aidonia Georgiadou	Laboratory Technician	
Approved by	Sven Kühn	Technical Manager	

Issued: August 19, 2024

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Accreditation No.: SCS 0108

Glossary

TSL	tissue simulating liquid
ConvF	sensitivity in TSL / NORM x,y,z
N/A	not applicable or not measured

Calibration is Performed According to the Following Standards

- IEC/IEEE 62209-1528, "Measurement Procedure For The Assessment Of Specific Absorption Rate Of Human Exposure To Radio Frequency Fields From Hand-Held And Body-Worn Wireless Communication Devices - Part 1528: Human Models, Instrumentation And Procedures (Frequency Range of 4 MHz to 10 GHz)", October 2020.
- KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

Additional Documentation

- DASY System Handbook

Methods Applied and Interpretation of Parameters

- *Measurement Conditions:* Further details are available from the Validation Report at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated.
- *Antenna Parameters with TSL:* The dipole is mounted with the spacer to position its feed point exactly below the center marking of the flat phantom section, with the arms oriented parallel to the body axis.
- *Feed Point Impedance and Return Loss:* These parameters are measured with the dipole positioned under the liquid filled phantom. The impedance stated is transformed from the measurement at the SMA connector to the feed point. The Return Loss ensures low reflected power. No uncertainty required.
- *Electrical Delay:* One-way delay between the SMA connector and the antenna feed point. No uncertainty required.
- *SAR measured:* SAR measured at the stated antenna input power.
- *SAR normalized:* SAR as measured, normalized to an input power of 1 W at the antenna connector.
- *SAR for nominal TSL parameters:* The measured TSL parameters are used to calculate the nominal SAR result.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor $k=2$, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY8 Module SAR	16.4.0
Extrapolation	Advanced Extrapolation	
Phantom	Modular Flat Phantom	
Distance Dipole Center - TSL	10 mm	with spacer
Zoom Scan Resolution	dx, dy = 5mm, dz = 1.5mm	Graded Ratio = 1.5 mm (Z direction)
Frequency	2550MHz $\pm$ 1MHz	

Head TSL parameters at 2550 MHz

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	39.1	1.91 mho/m
Measured Head TSL parameters	(22.0 $\pm$ 0.2)°C	37.5 $\pm$ 6%	1.95 mho/m $\pm$ 6%
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL at 2550 MHz

SAR averaged over 1 cm³ (1 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	24 dBm input power	13.6 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	54.1 W/kg $\pm$ 17.0% (k = 2)

SAR averaged over 10 cm³ (10 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	24 dBm input power	6.21 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	24.7 W/kg $\pm$ 16.5% (k = 2)

Appendix (Additional assessments outside the scope of SCS 0108)

Antenna Parameters with Head TSL at 2550 MHz

Impedance	50.4 Ω – 1.3 j Ω
Return Loss	-37.4 dB

General Antenna Parameters and Design

Electrical Delay (one direction)	1.151 ns
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After long term use with 100W radiated power, only a slight warming of the dipole near the feedpoint can be measured. The dipole is made of standard semirigid coaxial cable. The center conductor of the feeding line is directly connected to the second arm of the dipole. The antenna is therefore short-circuited for DC-signals. On some of the dipoles, small end caps are added to the dipole arms in order to improve matching when loaded according to the position as explained in the "Measurement Conditions" paragraph. The SAR data are not affected by this change. The overall dipole length is still according to the Standard. No excessive force must be applied to the dipole arms, because they might bend or the soldered connections near the feedpoint may be damaged.

Additional EUT Data

Manufactured by	SPEAG
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System Performance Check Report

Summary

Dipole	Frequency [MHz]	TSL	Power [dBm]
D2550V2 - SN1015	2550	HSL	24

Exposure Conditions

Phantom Section, TSL	Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	10		CW, 0--	2550, 0	7.35	1.95	37.5

Hardware Setup

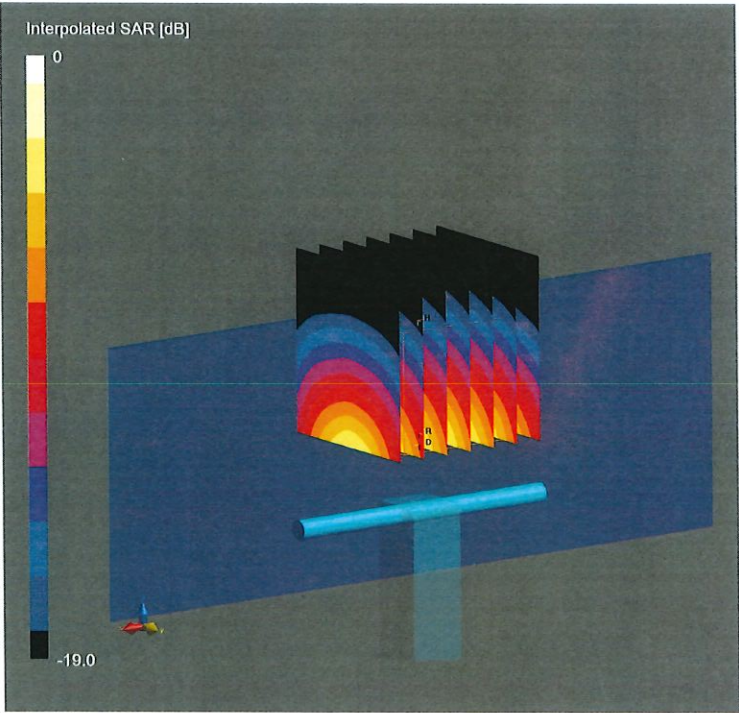
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
MFP V8.0 Center	HSL, 2024-08-16	EX3DV4 - SN7349, 2024-06-03	DAE4ip Sn1836, 2024-01-10

Scans Setup

	Zoom Scan
Grid Extents [mm]	30 x 30 x 30
Grid Steps [mm]	5.0 x 5.0 x 1.5
Sensor Surface [mm]	1.4
Graded Grid	Yes
Grading Ratio	1.5
MAIA	N/A
Surface Detection	VMS + 6p
Scan Method	Measured

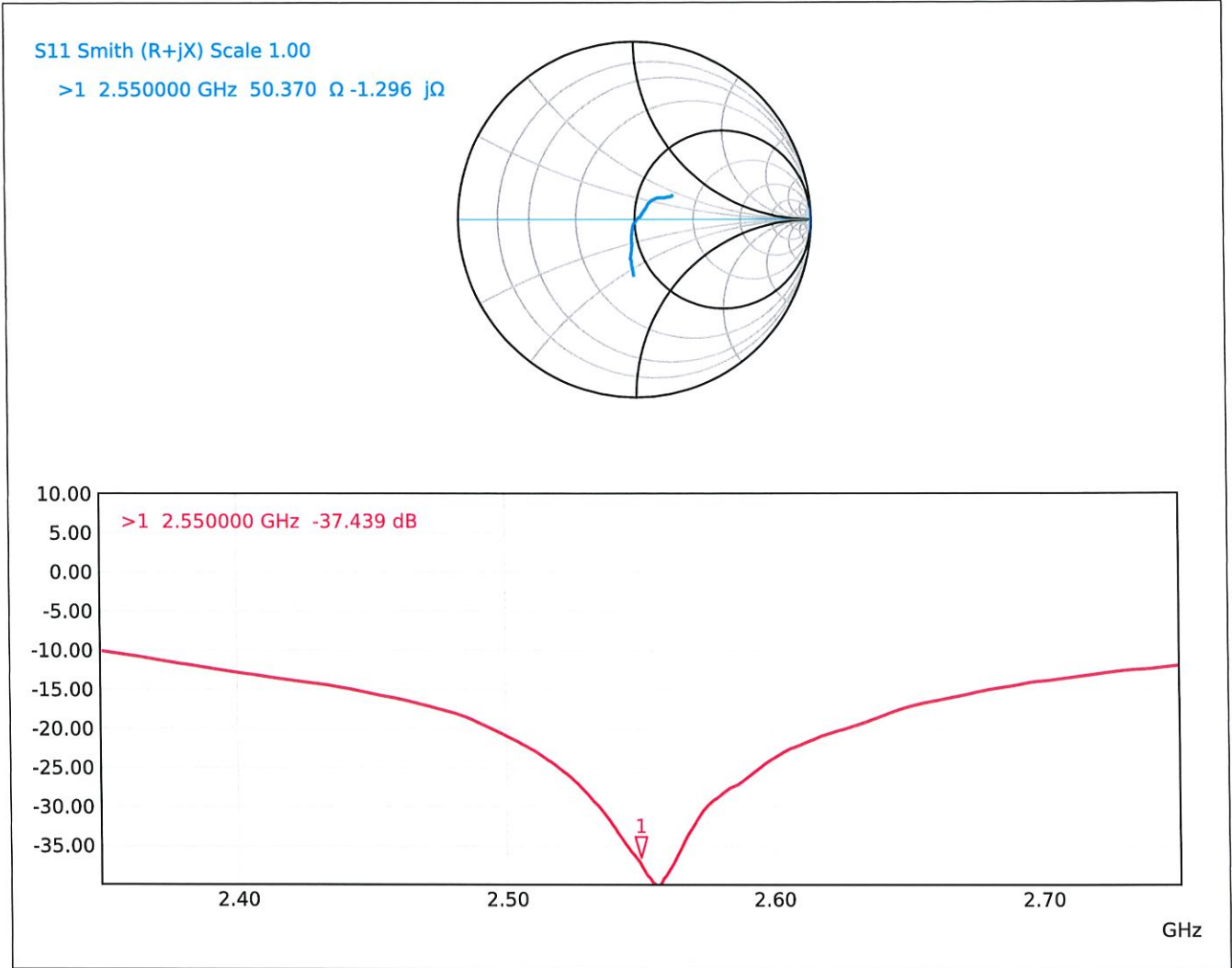
Measurement Results

	Zoom Scan
Date	2024-08-16
psSAR1g [W/Kg]	13.6
psSAR10g [W/Kg]	6.21
Power Drift [dB]	0.01
Power Scaling	Disabled
Scaling Factor [dB]	
TSL Correction	Positive / Negative



0 dB = 29.0 W/Kg

Impedance Measurement Plot for Head TSL





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Multilateral Agreement for the recognition of calibration certificates**

Accreditation No.: **SCS 0108**

Client

WSCT
Shenzhen

Certificate No.

D5GHzV2-1412_Oct24

CALIBRATION CERTIFICATE

Object **D5GHzV2 - SN: 1412**

Calibration procedure(s) **QA CAL-22.v7**
Calibration Procedure for SAR Validation Sources between 3 - 10 GHz

Calibration date **October 17, 2024**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^{\circ}\text{C}$ and humidity $< 70\%$.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Cal
Power Sensor R&S NRP-33T	SN: 100967	28-Mar-24 (No. 217-04038)	Mar-25
Power Sensor R&S NRP18A	SN: 101859	22-Jul-24 (No. 4030A315008547)	Jul-25
Spectrum Analyzer R&S FSV40	SN: 101832	25-Jan-24 (No. 4030-315007551)	Jan-25
Mismatch; Short [S4188] Attenuator [S4423]	SN: 1152	28-Mar-24 (No. 217-04050)	Mar-25
OCP DAK-12	SN: 1016	24-Sep-24 (No. OCP-DAK12-1016_Sep24)	Sep-25
OCP DAK-3.5	SN: 1249	23-Sep-24 (No. OCP-DAK3.5-1249_Sep24)	Sep-25
Reference Probe EX3DV4	SN: 7349	03-Jun-24 (No. EX3-7349_Jun24)	Jun-25
DAE4ip	SN: 1836	10-Jan-24 (No. DAE4ip-1836_Jan24)	Jan-25

Secondary Standards	ID	Check Date (in house)	Scheduled Check
ACAD Source Box	SN: 1000	28-May-24 (No. 675-ACAD_Source_Box-240528)	May-25
Signal Generator R&S SMB100A	SN: 182081	28-May-24 (No. 675-CAL16-S4588-240528)	May-25
Mismatch; SMA	SN: 1102	22-May-24 (No. 675-Mismatch_SMA-240522)	May-25

	Name	Function	Signature
Calibrated by	Paulo Pina	Laboratory Technician	
Approved by	Sven Kühn	Technical Manager	

Issued: October 17, 2024

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Calibration Laboratory of

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Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerischer Kalibrierdienst
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S Swiss Calibration Service

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- KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

Additional Documentation

- DASY System Handbook

Methods Applied and Interpretation of Parameters

- *Measurement Conditions*: Further details are available from the Validation Report at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated.
- *Antenna Parameters with TSL*: The dipole is mounted with the spacer to position its feed point exactly below the center marking of the flat phantom section, with the arms oriented parallel to the body axis.
- *Feed Point Impedance and Return Loss*: These parameters are measured with the dipole positioned under the liquid filled phantom. The impedance stated is transformed from the measurement at the SMA connector to the feed point. The Return Loss ensures low reflected power. No uncertainty required.
- *Electrical Delay*: One-way delay between the SMA connector and the antenna feed point. No uncertainty required.
- *SAR measured*: SAR measured at the stated antenna input power.
- *SAR normalized*: SAR as measured, normalized to an input power of 1 W at the antenna connector.
- *SAR for nominal TSL parameters*: The measured TSL parameters are used to calculate the nominal SAR result.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor $k=2$, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY8 Module SAR	16.4.0
Extrapolation	Advanced Extrapolation	
Phantom	Modular Flat Phantom	
Distance Dipole Center - TSL	10 mm	with spacer
Zoom Scan Resolution	dx, dy = 4mm, dz = 1.4mm	Graded Ratio = 1.4 mm (Z direction)
Frequency	5200MHz $\pm$ 1MHz 5300MHz $\pm$ 1MHz 5500MHz $\pm$ 1MHz 5600MHz $\pm$ 1MHz 5800MHz $\pm$ 1MHz	

Head TSL parameters at 5200 MHz

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	36.0	4.66 mho/m
Measured Head TSL parameters	(22.0 $\pm$ 0.2)°C	35.9 $\pm$ 6%	4.51 mho/m $\pm$ 6%
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL at 5200 MHz

SAR averaged over 1 cm³ (1 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	7.60 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	76.0 W/kg $\pm$ 19.9% (k = 2)

SAR averaged over 10 cm³ (10 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	2.20 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	22.0 W/kg $\pm$ 19.5% (k = 2)

Head TSL parameters at 5300 MHz

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	35.9	4.76 mho/m
Measured Head TSL parameters	(22.0 ±0.2)°C	35.7 ±6%	4.60 mho/m ±6%
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL at 5300 MHz

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	8.06 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	80.6 W/kg ±19.9% (k = 2)

SAR averaged over 10 cm ³ (10 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	2.33 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	23.3 W/kg ±19.5% (k = 2)

Head TSL parameters at 5500 MHz

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	35.6	4.96 mho/m
Measured Head TSL parameters	(22.0 ±0.2)°C	35.3 ±6%	4.82 mho/m ±6%
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL at 5500 MHz

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	8.56 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	85.6 W/kg ±19.9% (k = 2)

SAR averaged over 10 cm ³ (10 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	2.45 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	24.5 W/kg ±19.5% (k = 2)

Head TSL parameters at 5600 MHz

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	35.5	5.07 mho/m
Measured Head TSL parameters	(22.0 ±0.2)°C	35.1 ±6%	4.94 mho/m ±6%
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL at 5600 MHz

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	8.33 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	83.3 W/kg ±19.9% (k = 2)

SAR averaged over 10 cm ³ (10 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	2.41 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	24.1 W/kg ±19.5% (k = 2)

Head TSL parameters at 5800 MHz

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	35.3	5.27 mho/m
Measured Head TSL parameters	(22.0 ±0.2)°C	34.9 ±6%	5.15 mho/m ±6%
Head TSL temperature change during test	< 0.5 °C		

SAR result with Head TSL at 5800 MHz

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	7.90 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	79.0 W/kg ±19.9% (k = 2)

SAR averaged over 10 cm ³ (10 g) of Head TSL	Condition	
SAR for nominal Head TSL parameters	20 dBm input power	2.27 W/kg
SAR for nominal Head TSL parameters	normalized to 1W	22.7 W/kg ±19.5% (k = 2)

Appendix (Additional assessments outside the scope of SCS 0108)**Antenna Parameters with Head TSL at 5200 MHz**

Impedance	53.3 Ω – 4.8 j Ω
Return Loss	-25.0 dB

Antenna Parameters with Head TSL at 5300 MHz

Impedance	48.4 Ω + 2.0 j Ω
Return Loss	-31.6 dB

Antenna Parameters with Head TSL at 5500 MHz

Impedance	47.6 Ω – 2.2 j Ω
Return Loss	-29.5 dB

Antenna Parameters with Head TSL at 5600 MHz

Impedance	55.9 Ω + 0.5 j Ω
Return Loss	-25.1 dB

Antenna Parameters with Head TSL at 5800 MHz

Impedance	50.5 Ω + 4.2 j Ω
Return Loss	-27.5 dB

General Antenna Parameters and Design

Electrical Delay (one direction)	1.207 ns
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After long term use with 100W radiated power, only a slight warming of the dipole near the feedpoint can be measured. The dipole is made of standard semirigid coaxial cable. The center conductor of the feeding line is directly connected to the second arm of the dipole. The antenna is therefore short-circuited for DC-signals. On some of the dipoles, small end caps are added to the dipole arms in order to improve matching when loaded according to the position as explained in the "Measurement Conditions" paragraph. The SAR data are not affected by this change. The overall dipole length is still according to the Standard. No excessive force must be applied to the dipole arms, because they might bend or the soldered connections near the feedpoint may be damaged.

Additional EUT Data

Manufactured by	SPEAG
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System Performance Check Report

Summary

Dipole	Frequency [MHz]	TSL	Power [dBm]
D5GHzV2 - SN1412	5200	HSL	20

Exposure Conditions

Phantom Section, TSL	Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	10		CW, 0--	5200, 0	5.68	4.51	35.9

Hardware Setup

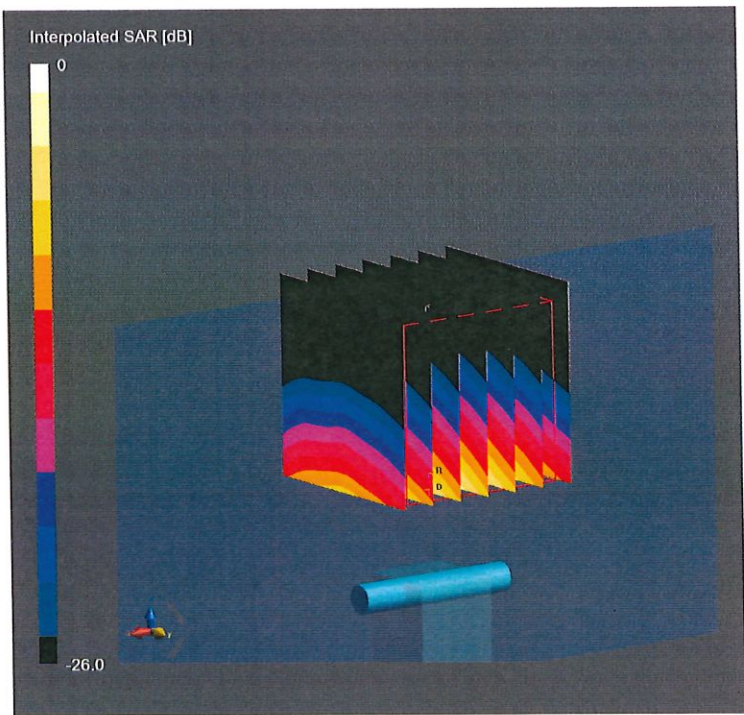
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
MFP V8.0 Center	HSL, 2024-10-17	EX3DV4 - SN7349, 2024-06-03	DAE4ip Sn1836, 2024-01-10

Scans Setup

	Zoom Scan
Grid Extents [mm]	22 x 22 x 22
Grid Steps [mm]	4.0 x 4.0 x 1.4
Sensor Surface [mm]	1.4
Graded Grid	Yes
Grading Ratio	1.4
MAIA	N/A
Surface Detection	VMS + 6p
Scan Method	Measured

Measurement Results

	Zoom Scan
Date	2024-10-17
psSAR1g [W/Kg]	7.60
psSAR10g [W/Kg]	2.20
Power Drift [dB]	0.00
Power Scaling	Disabled
Scaling Factor [dB]	
TSL Correction	Positive / Negative



0 dB = 30.4 W/Kg

System Performance Check Report

Summary

Dipole	Frequency [MHz]	TSL	Power [dBm]
D5GHzV2 - SN1412	5300	HSL	20

Exposure Conditions

Phantom Section, TSL	Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	10		CW, 0--	5300, 0	5.45	4.60	35.7

Hardware Setup

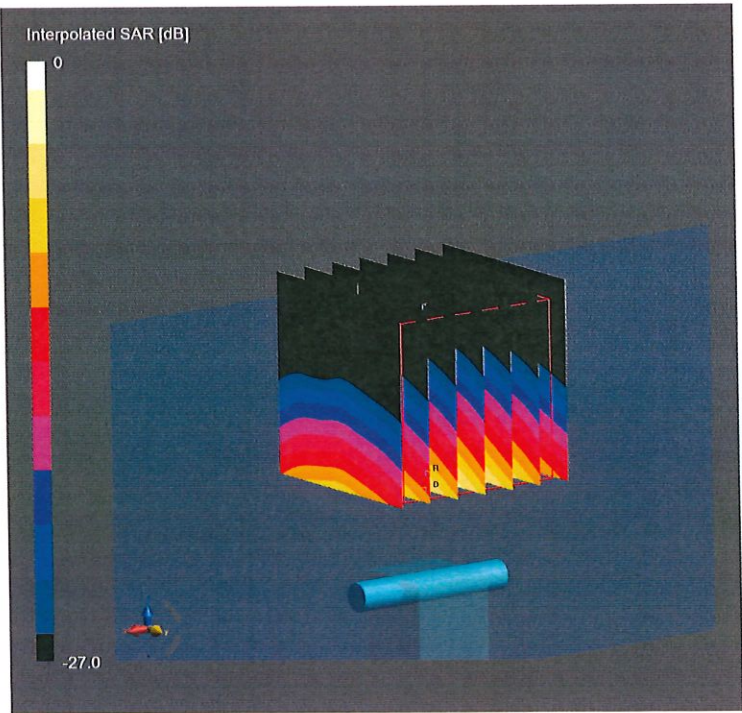
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
MFP V8.0 Center	HSL, 2024-10-17	EX3DV4 - SN7349, 2024-06-03	DAE4lp Sn1836, 2024-01-10

Scans Setup

	Zoom Scan
Grid Extents [mm]	22 x 22 x 22
Grid Steps [mm]	4.0 x 4.0 x 1.4
Sensor Surface [mm]	1.4
Graded Grid	Yes
Grading Ratio	1.4
MAIA	N/A
Surface Detection	VMS + 6p
Scan Method	Measured

Measurement Results

	Zoom Scan
Date	2024-10-17
psSAR1g [W/Kg]	8.06
psSAR10g [W/Kg]	2.33
Power Drift [dB]	0.00
Power Scaling	Disabled
Scaling Factor [dB]	
TSL Correction	Positive / Negative



0 dB = 33.1 W/Kg

System Performance Check Report

Summary

Dipole	Frequency [MHz]	TSL	Power [dBm]
D5GHzV2 - SN1412	5500	HSL	20

Exposure Conditions

Phantom Section, TSL	Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	10		CW, 0--	5500, 0	5.07	4.82	35.3

Hardware Setup

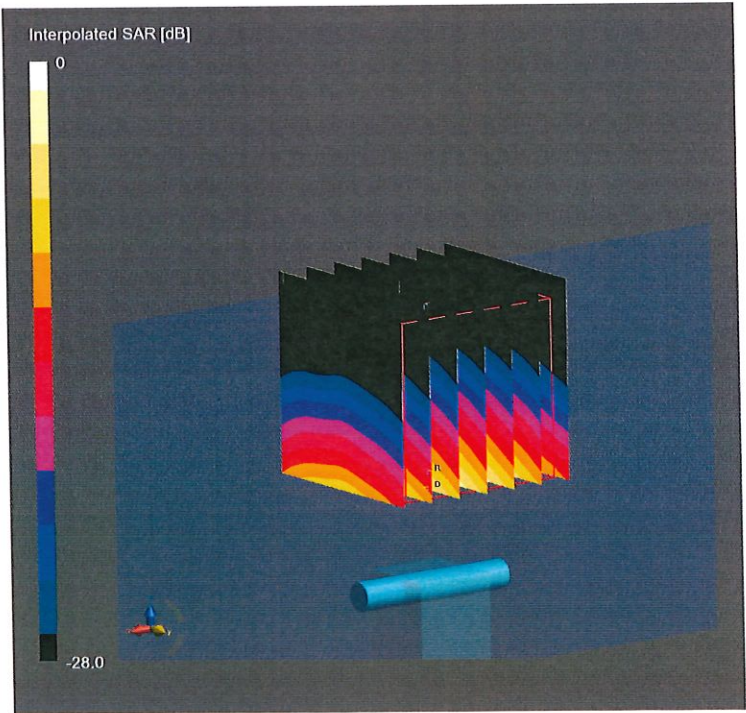
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
MFP V8.0 Center	HSL, 2024-10-17	EX3DV4 - SN7349, 2024-06-03	DAE4ip Sn1836, 2024-01-10

Scans Setup

	Zoom Scan
Grid Extents [mm]	22 x 22 x 22
Grid Steps [mm]	4.0 x 4.0 x 1.4
Sensor Surface [mm]	1.4
Graded Grid	Yes
Grading Ratio	1.4
MAIA	N/A
Surface Detection	VMS + 6p
Scan Method	Measured

Measurement Results

	Zoom Scan
Date	2024-10-17
psSAR1g [W/Kg]	8.56
psSAR10g [W/Kg]	2.45
Power Drift [dB]	0.00
Power Scaling	Disabled
Scaling Factor [dB]	
TSL Correction	Positive / Negative



0 dB = 36.7 W/Kg

System Performance Check Report

Summary

Dipole	Frequency [MHz]	TSL	Power [dBm]
D5GHzV2 - SN1412	5600	HSL	20

Exposure Conditions

Phantom Section, TSL	Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	10		CW, 0--	5600, 0	5.03	4.94	35.1

Hardware Setup

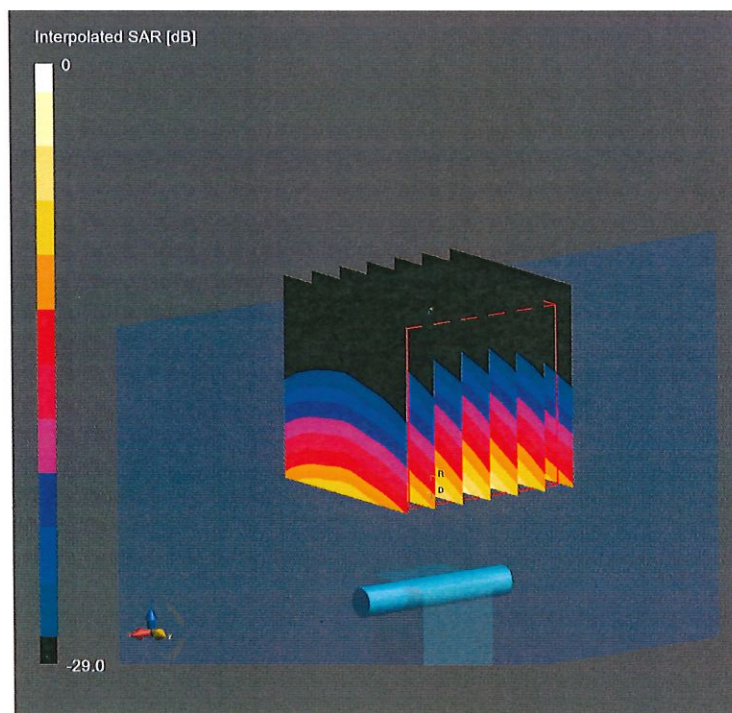
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
MFP V8.0 Center	HSL, 2024-10-17	EX3DV4 - SN7349, 2024-06-03	DAE4ip Sn1836, 2024-01-10

Scans Setup

	Zoom Scan
Grid Extents [mm]	22 x 22 x 22
Grid Steps [mm]	4.0 x 4.0 x 1.4
Sensor Surface [mm]	1.4
Graded Grid	Yes
Grading Ratio	1.4
MAIA	N/A
Surface Detection	VMS + 6p
Scan Method	Measured

Measurement Results

	Zoom Scan
Date	2024-10-17
psSAR1g [W/Kg]	8.33
psSAR10g [W/Kg]	2.41
Power Drift [dB]	0.00
Power Scaling	Disabled
Scaling Factor [dB]	
TSL Correction	Positive / Negative



System Performance Check Report

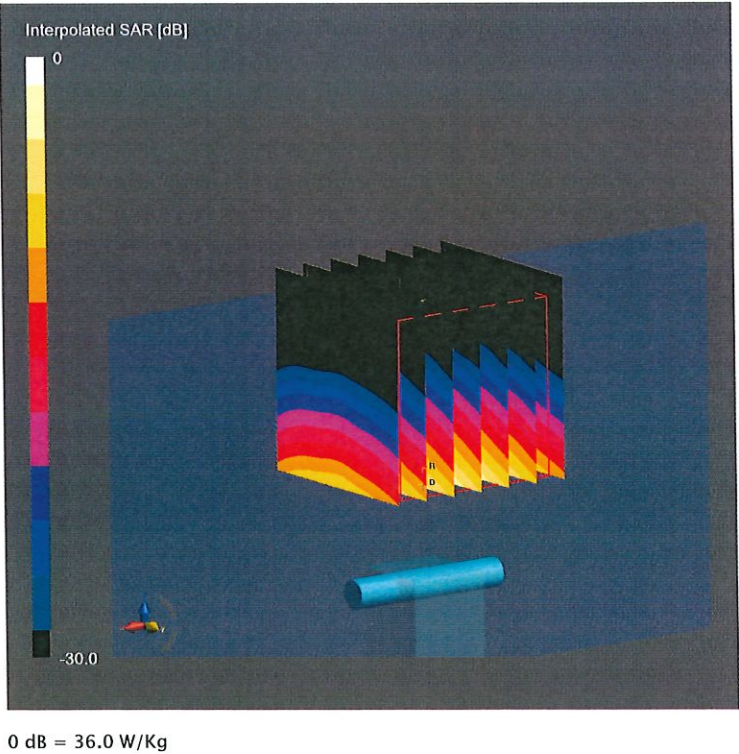
Summary			
Dipole	Frequency [MHz]	TSL	Power [dBm]
D5GHzV2 – SN1412	5800	HSL	20

Exposure Conditions							
Phantom Section, TSL	Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	10		CW, 0--	5800, 0	5.08	5.15	34.9

Hardware Setup			
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
MFP V8.0 Center	HSL, 2024-10-17	EX3DV4 – SN7349, 2024-06-03	DAE4ip Sn1836, 2024-01-10

Scans Setup	
	Zoom Scan
Grid Extents [mm]	22 x 22 x 22
Grid Steps [mm]	4.0 x 4.0 x 1.4
Sensor Surface [mm]	1.4
Graded Grid	Yes
Grading Ratio	1.4
MAIA	N/A
Surface Detection	VMS + 6p
Scan Method	Measured

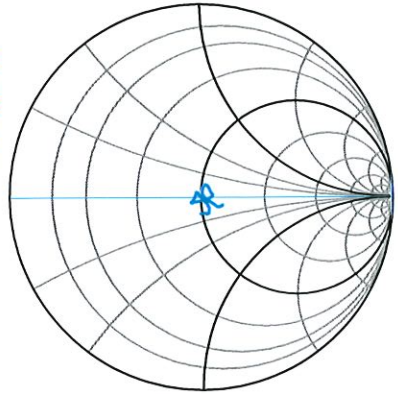
Measurement Results	
	Zoom Scan
Date	2024-10-17
psSAR1g [W/Kg]	7.90
psSAR10g [W/Kg]	2.27
Power Drift [dB]	-0.01
Power Scaling	Disabled
Scaling Factor [dB]	
TSL Correction	Positive / Negative



Impedance Measurement Plot for Head TSL

S11 Smith (R+jX) Scale 1.00

>1	5.200000 GHz	53.331 Ω	-4.787 j Ω
>2	5.300000 GHz	48.405 Ω	2.049 j Ω
>3	5.500000 GHz	47.552 Ω	-2.187 j Ω
>4	5.600000 GHz	55.889 Ω	0.477 j Ω
>5	5.800000 GHz	50.472 Ω	4.191 j Ω





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Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 0108**

Client **WSCT**
Shenzhen

Certificate No: **OCP-DAK3.5-1363_Nov24**

CALIBRATION CERTIFICATE

Object **DAK-3.5 - SN: 1363**

Calibration procedure(s) **QA CAL-33.v3**
Calibration of dielectric parameter probes

Calibration date: **November 5, 2024**

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Certificate No.)	Scheduled Calibration
OCP DAK-3.5 (weighted)	SN: 1249	23-Sep-24 (OCP-DAK3.5-1249_Sep24)	Sep-25
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Rohde & Schwarz ZVA67	T4383	1-Oct-24 (in house check Oct-24)	Oct-25
Digital Thermometer DTM3000	4026	07-Feb-24 (DTM-4026_Feb24)	Feb-25
Methanol 99.9% Type 34860	STBH5818	06-May-19 (bottle opened, check May-24)	May-25
Ethanol 99.9% Type 1.0983	241014-1	14-Oct-20 (bottle opened, check Oct-24)	Oct-25
Head Liquid, HBBL U16	200311-0	11-Mar-20 (in house check May-24)	May-25
0.1 mol/L NaCl solution	190926-1	20-Sep-19 (in house check May-24)	May-25
0.05 mol/L NaCl solution	190926-0	20-Sep-19 (in house check May-24)	May-25
Head Gel, SLAGH U08 AA-B	200227-1	07-Apr-20 (in house check Apr-24)	Apr-25
Eccostock0005	1507101	01-Jul-15 (in house check May-24)	May-25

	Name	Function	Signature
Calibrated by:	Cindy Karina	External Engineer	
Approved by:	Sven Kühn	Technical Manager	

Issued: November 5, 2024

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.



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Description of the dielectric probe

Dielectric probes are used to measure the dielectric parameters of tissue simulating media in a wide frequency range. The complex permittivity $\epsilon_r^* = (\epsilon'/\epsilon_0) - j(\epsilon''/\epsilon_0)$ is determined from the S parameters measured with a vector network analyzer (VNA) with software specific to the probe type. The parameters of interest e.g. in standards [1, 2, 3] and for other applications are presented are calculated as follows:

(Relative) permittivity ϵ' (real part of $\epsilon_r^* = (\epsilon'/\epsilon_0) - j(\epsilon''/\epsilon_0)$ where $\epsilon_0 = 8.854 \text{ pF/m}$ is the permittivity in free space)

Conductivity $\sigma = 2 \pi f \epsilon'' \epsilon_0$,

Loss Tangent = (ϵ''/ϵ')

The **OCF** (open ended coaxial) is a cut off section of 50 Ohm transmission line, similar to the system described in [1, 2, 3, 5], used for contact measurement. The material is measured either by touching the probe to the surface of a solid/gel or by immersing it into a liquid media. The electromagnetic fields at the probe end fringe into the material to be measured, and its parameters are determined from the change of the S_{11} parameters. With larger diameter of the dielectrics, the probe can be used down to lower frequencies.

The flange surrounding the active area shapes the near field similar to a semi-infinite geometry and is inserted fully into the measured lossy liquid.

The probe is connected with a phase and amplitude stable cable to a VNA which is then calibrated with Open, Short and a Liquid with well-known parameters. All parts in the setup influencing the amplitude and phase of the signal are important and shall remain stable.

Handling of the item

Before usage, the active probe area has to be cleaned from any material residuals potentially contaminating the reference standards. The metal and dielectric surface must be protected to keep the precision of the critical mechanical dimensions. The connector and cable quality are critical; any movements between calibration and measurement shall be avoided. The temperature must be stable and must not differ from the material temperature.

Methods Applied and Interpretation of Parameters

The calibration of the dielectric probe system is done in the steps described below for the desired frequency range and calibration package (SAR/MRI liquids, Semi-solid/solid material). Because the standard calibration in step 3 is critical for the results in steps 4 to 8, the sequence 3 to 8 is repeated 3 times. As a result, the result from these 3 sets is represented.

1. Configuration and mechanical / optical status.
2. Measurement resolution is 5 MHz from 10 to 300 MHz, 50 MHz from 300 to 6000 MHz and 250 MHz from 6 to 20 GHz.
3. Standard calibration uses Air / Short / Liquid. 1 liter liquid quantity is used to reduce the influence the reflections. The liquid type is selected depending on the lowest frequency and probe diameter:
DAK-1.2, DAK-3.5, Agilent OCP: de-ionized water (approx. 22 °C)
DAK-12: saline solution with static conductivity 1 S/m (approx. 22 °C)
NPL OCP: pure ethanol (approx. 22 °C)
4. The cable used in the setup stays in a fixed position, i.e. the probe is fixed and measuring from the top in an angle of typ. 20° from the vertical axis. For DAK and Agilent probes, the refresh function (air standard) is used previous to the individual measurements in order to compensate for possible deviations from cable movements. After insertion of the probe into a liquid, the possible air bubbles are removed from the active surface.
5. Measurement of multiple shorts if not already available from the calibration in the previous step (NPL). Evaluation of the deviation from the previous calibration short with graphical representation of the complex quantities and magnitude over the frequency range. Probe specific short is used. This assessment shows ability to define a short circuit at the end of the probe for the VNA calibration in the setup which is essential at high frequencies and depends on the probe surface quality.
6. Measurement of validation liquids in a quantity of 1 liter at well defined temperature. Evaluation of the deviations from the target. The targets base on traceable data from reference sources. The deviation of the measurement is graphically presented for permittivity and conductivity (for lossy liquids) or loss tangent (for low losses at low frequencies).
7. Measurement of lossy liquids in a quantity of 1 liter at well defined temperature. Head tissue simulating liquid or saline solution with 0.5 S/m static conductivity are representative. The target data base on traceable data from reference sources or from multiple measurements with precision reference probes or different evaluations such as transmission line or slotted line methods. Evaluation of the deviation from the target and graphical representation for permittivity and conductivity over the frequency range
8. Semi-solid / solid material calibration:
Measurements of an elastic lossy broadband semi-solid gel with parameters close to the head tissue target. Measurements of a planar very low loss solid microwave-substrate. The average of 4 measurements of the same sample at different location is shown as a single result. The deviation of the permittivity and conductivity from the reference data is evaluated.
Measurements of a planar very low loss solid microwave-substrate. The average of 4 measurements of the same sample at different location is shown as a single result. The relative deviation of the permittivity and the absolute deviation of the loss tangent is evaluated.
The targets base on multiple measurements (on the same material batch at identical temperature) on convex and planar surfaces with precision reference OCP.

The measurement on semi-solid / solid materials is sensitive to the quality and planarity of the probe contact area, such as air gaps due to imperfect probes (resulting lower permittivity values).

9. Table for the probe uncertainty: The uncertainty of the probe depending on probe type, size, material parameter range and frequency is given in a table. It represents the best measurement capability of the specific probe but does not include the material (deviation from the target values).
10. Appendix with detailed results of all measurements with the uncertainties for the specific measurement. In addition to the probe uncertainty (see above), it includes the uncertainty of the reference material used for the measurement. A set of results from independent calibrations represents the capability of the setup and the lossy materials used, including the precision of the measured material and the influence of temperature deviations. Temperature and operator influence was minimized and gives a good indication of the achievable repeatability of a measurement.
11. Summary assessment of the measured deviations and detailed comments if not typical for the probe type.

Dielectric probe identification and configuration data

Item description

Probe type	OCP Open-ended coaxial probe
Probe name	SPEAG Dielectric Assessment Kit DAK-3.5
Type No	SM DAK 040 CA
Serial No	1363
Description	Open-ended coaxial probe with flange Flange diameter: 19.0 mm Dielectric diameter: 3.5 mm Material: stainless steel
Connector 1	PC 3.5 pos.
Software version	DAK Measurement Solver 3.0.6.34 Calibration Type: Air / short / water (set to measured water temp.) Probe type: "DAK3.5" (software setting)
Further settings	VNA bandwidth setting: 50 Hz

SCS 0108 Accessories used for customer probe calibration

Cable	Huber & Suhner Sucoflex 100, SN: 512046/126, length 1 m, PC3.5 neg. – PC3.5 neg.
Short	DAK-3.5 shorting block, type SM DAK 200 BA Contact area covered with cleaned Cu stripe

Additional items used during measurements

Adapter 1	PC3.5 pos. – PC1.85 (VNA side)
Adapter 2	PC3.5 pos. – PC3.5 neg. (probe side)

Notes

- Before the calibration, the connectors of the probe and cable were inspected and cleaned.
- Probe visual inspection: according to requirements
- Short inspection: according to the requirements

Probe Uncertainty

The following tables provide material and frequency specific uncertainties ($k=2$) for the dielectric probe. The values in the tables represent the measurement capability for the probe when measuring a material in the indicated parameter range. They include all uncertainties of

- probe system
- possible systematic errors due to the design
- calibration
- temperature differences during the calibration and measurements, as described,
- VNA noise

Apart from the material used for the calibration (de-ionized water), material uncertainties of the reference materials used during the measurement in Appendix A are not included in these tables.

DAK-3.5				
Permittivity range		Frequency range	(sigma / LT range)	Unc. ($k=2$)
	1 – 15	200 MHz - 3 GHz	LT < 0.1	2.4%
		3 GHz - 6 GHz	LT < 0.1	2.0%
		6 GHz - 20 GHz	LT < 0.1	2.1%
		6 GHz - 20 GHz	sigma > 1	3.5%
	10 – 40	200 MHz - 3 GHz	sigma : 1 – 10 S/m	1.9%
		3 GHz - 6 GHz	sigma : 1 – 10 S/m	2.3%
		6 GHz - 20 GHz	sigma > 10 S/m	3.5%
	35 – 100	200 MHz - 3 GHz	sigma : 1 – 10 S/m	1.8%
		3 GHz - 6 GHz	sigma : 1 – 10 S/m	1.9%
		6 GHz - 20 GHz	sigma > 10 S/m	2.4%
Conductivity range (S/m)		Frequency range	(epsilon / LT range)	Unc. ($k=2$)
	1 – 10	200 MHz - 3 GHz	eps : 35 - 100	2.7%
		3 GHz - 6 GHz	eps : 35 - 100	3.0%
		6 GHz - 20 GHz	eps : 10 - 40	3.0%
Loss tangent range		Frequency range	(epsilon / LT range)	Unc. ($k=2$)
	< 0.1	200 MHz - 3 GHz	eps : 1 - 15	0.03
		3 GHz - 6 GHz	eps : 1 - 15	0.03
		6 GHz - 20 GHz	eps : 1 - 15	0.03

Calibration Results

Uncertainty limits ($k=2$) for the material measurements in the figures of Appendix A are represented with red dashed lines. These uncertainties contain - in addition to probe uncertainty - the uncertainty of the material target parameter determination.

The measurements show the results obtained from independent calibrations for the same material. The differences between the individual measurement curves give therefore an indication for the obtainable repeatability and shall lie within the uncertainties stated in the tables.

Materials for DAK-3.5 calibration:

Appendix A with curves for Ethanol, HBBL, and 0.05 mol/L NaCl solution (200 MHz - 6 GHz, optional 20 GHz), HS gel and low loss solid substrate are optional.*

** Effective immediately, methanol will be replaced with the safer and more environmentally-friendly ethanol as the validation liquid. Each batch of ethanol is calibrated using a methanol reference, ensuring that the validation process is both traceable and consistent with prior measurements.*

Appendix A: Detailed Results

A.1 Probe appearance and calibration sequence

A.1.1 Appearance

The OCP appearance is fully according to the expectations:

- the flange surface is intact

A.1.2 Calibration sequence

The following sequence was repeated 3 times in the low frequency range from 200 – 300 MHz in 5 MHz steps and in the high frequency range from 300 to 6000 MHz in 50 MHz steps, and from 6 GHz to 20 GHz in 250 MHz steps.

- Air
- Short 1 short, then immediate verification with a second short (with eventual repetition)
- Water De-ionized water, temperature measured and set in the software (for DAK-12 0.1 mol/L saline solution, temperature measured and set in the software)
- Methanol Pure methanol, temperature measured and set in the software
- Ethanol Pure ethanol, temperature measured and set in the software
- Liquids Measurement of further liquids (e.g. Head tissue simulating liquid and 0.05 mol/l saline)
- Cleaning Probe washed with water and isopropanol at the end of the sequence.
- Shorts 4 additional separate short measurements to determine the deviation from the original
- Refresh Refresh with Air
- Solid 4 separate solid low loss planar substrate measurements to determine one average (optional)
- Semisolid 4 separate head gel measurements on fresh intact surface to determine one average (optional)
- Cleaning Probe washed with water and isopropanol at the end of the sequence

Evaluation of the additional shorts from the calibrated (ideal) short point at the left edge of the Smith Chart, represented as magnitude over the frequency range (fig. 2.1.x) and in polar representation (fig. 2.2.x).

Evaluation of the Liquid measurements and representation of the permittivity and conductivity deviation from their reference data at the measurement temperature. The results of each of the 3 calibrations is shown in the appendix for each material (fig. 3ff) in black, red, blue. The red dashed line shows the uncertainty of the reference material parameter determination.

Evaluation of the Semisolid measurements (optional) by representing the 3 average deviations (each resulting from the 4 separate measurements per set), equivalent to the liquid measurement. Representation of the permittivity and conductivity deviation from their reference data at the nominal temperature.

Evaluation of the Solid measurements (optional) by representing the 3 average deviations (each resulting from the 4 separate measurements per set), equivalent to the liquid measurement. Representation of the permittivity deviation from their reference data and the loss tangent at the nominal temperature.